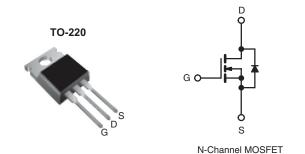


Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	8	800			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	6.5			
Q _g (Max.) (nC)	3	38			
Q _{gs} (nC)	5	5.0			
Q _{gd} (nC)	21				
Configuration	Sir	Single			



FEATURES

- · Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- · Fast Switching
- · Ease of Paralleling
- · Simple Drive Requirements
- Lead (Pb)-free Available



DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION			
Package	TO-220		
Load (Dh) free	IRFBE20PbF		
Lead (Pb)-free	SiHFBE20-E3		
SnPb	IRFBE20		
SHED	SiHFBE20		

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	800	V	
Gate-Source Voltage			V_{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	1-	1.8	А	
		T _C = 100 °C	ID	1.2		
Pulsed Drain Current ^a			I _{DM}	7.2	-	
Linear Derating Factor				0.43	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	180	mJ	
Repetitive Avalanche Current ^a			I _{AR}	1.8	А	
Repetitive Avalanche Energy ^a			E _{AR}	5.4	mJ	
Maximum Power Dissipation	T _C = 25 °C		P _D	54	W	
Peak Diode Recovery dV/dtc			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
				1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 104 mH, R_G = 25 Ω , I_{AS} = 1.8 A (see fig. 12). c. $I_{SD} \le 1.8$ A, $dI/dt \le 80$ A/ μ s, $V_{DD} \le 600$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFBE20, SiHFBE20

Vishay Siliconix



THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.3	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		800	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _G	V _{GS} = ± 20 V		-	± 100	nA
	I _{DSS}	V _{DS} = 800 V, V _{GS} = 0 V		-	-	100	μΑ
Zero Gate Voltage Drain Current		V _{DS} = 640 V, V	V _{DS} = 640 V, V _{GS} = 0 V, T _J = 125 °C		-	500	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1.1 A ^b	-	-	6.5	Ω
Forward Transconductance	9 fs	V _{DS} = 100 V, I _D = 1.1 A ^b		0.80	-	-	S
Dynamic					ı		
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	530	-	pF
Output Capacitance	C _{oss}			-	150	-	
Reverse Transfer Capacitance	C _{rss}			-	90	-	
Total Gate Charge	Qg			-	-	38	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 1.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b	-	-	5.0	
Gate-Drain Charge	Q _{gd}	see lig. 6 and 13°	see lig. o and 15	-	-	21	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 1.8 \text{ A},$ $R_{G} = 18 \Omega, R_{D} = 230 \Omega, \text{ see fig. } 10^{b}$		-	8.2	-	- ns
Rise Time	t _r			-	17	-	
Turn-Off Delay Time	t _{d(off)}			-	58	-	
Fall Time	t _f			-	27	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	- nH
Internal Source Inductance	L _S			-	7.5	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	1.8	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	7.2	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 1.8 A, V _{GS} = 0 V ^b		-	-	1.4	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 1.8 A, dl/dt = 100 A/μs ^b		-	380	570	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.94	1.4	μС
Forward Turn-On Time	t _{on}	Intrinsic turn	-on is dor	ninated b	v Ls and	L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

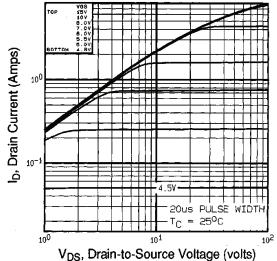
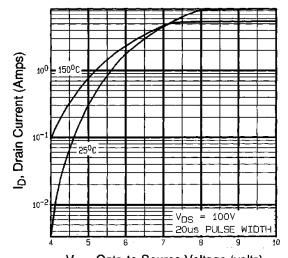
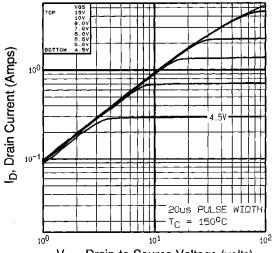


Fig. 1 - Typical Output Characteristics, T_C = 25 °C



V_{GS}, Gate-to-Source Voltage (volts) Fig. 3 - Typical Transfer Characteristics



 V_{DS} , Drain-to-Source Voltage (volts) Fig. 2 - Typical Output Characteristics, T_C = 150 °C

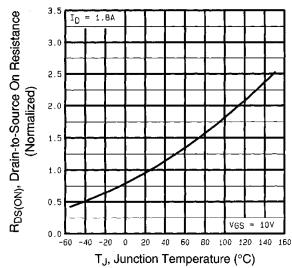


Fig. 4 - Normalized On-Resistance vs. Temperature

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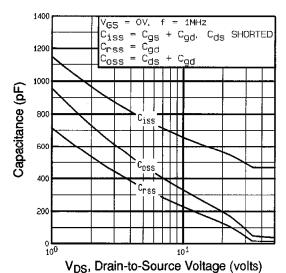


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

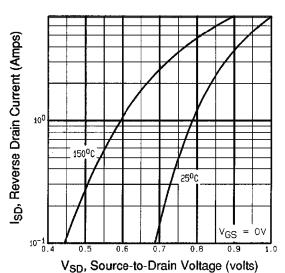


Fig. 7 - Typical Source-Drain Diode Forward Voltage

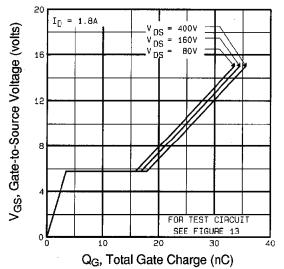
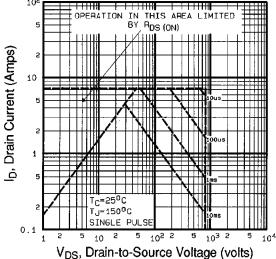
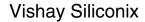


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



V_{DS}, Drain-to-Source Voltage (Volts) Fig. 8 - Maximum Safe Operating Area





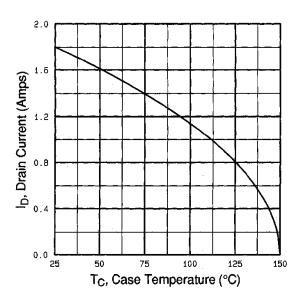


Fig. 9 - Maximum Drain Current vs. Case Temperature

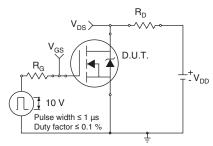


Fig. 10a - Switching Time Test Circuit

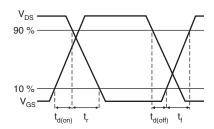


Fig. 10b - Switching Time Waveforms

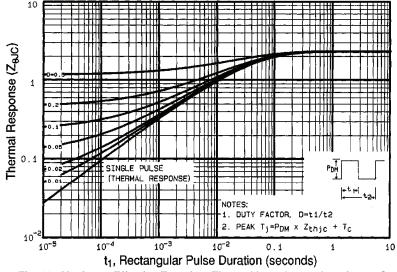


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

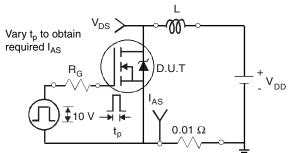


Fig. 12a - Unclamped Inductive Test Circuit

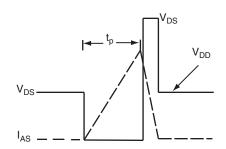


Fig. 12b - Unclamped Inductive Waveforms

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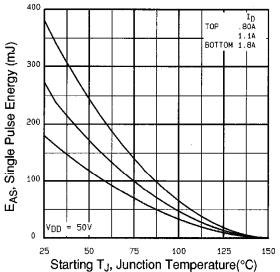


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

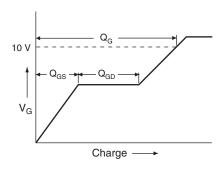


Fig. 13a - Basic Gate Charge Waveform

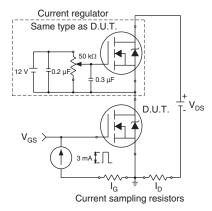
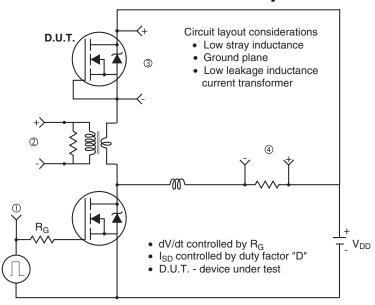
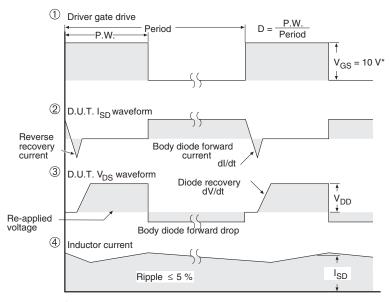


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* V_{GS} = 5 V for logic level and 3 V drive devices

Fig. 14 - For N-Channel

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